

Description

The HM35N03Q uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

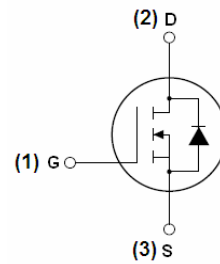
General Features

- $V_{DS} = 30V, I_D = 35A$
 $R_{DS(ON)} < 5.5m\Omega @ V_{GS} = 10V$
 $R_{DS(ON)} < 9.5m\Omega @ V_{GS} = 4.5V$
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

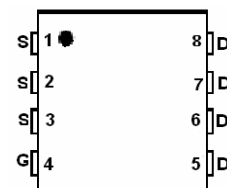
Application

- Secondary side synchronous rectifier
- High side switch in POL DC/DC converter

100% UIS TESTED!



Schematic diagram



DFN 3x3 EP top view

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|----------|----------------|-----------|------------|----------|
| HM35N03Q | HM35N03Q | DFN 3x3 EP | - | - | - |

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|---|----------------|------------|---------------|
| Drain-Source Voltage | V_{DS} | 30 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | 35 | A |
| Pulsed Drain Current | I_{DM} | 120 | A |
| Maximum Power Dissipation | P_D | 35 | W |
| Derating factor | | 0.28 | W/ $^\circ C$ |
| Single pulse avalanche energy ^(Note 5) | E_{AS} | 150 | mJ |
| Operating Junction and Storage Temperature Range | T_J, T_{STG} | -55 To 150 | $^\circ C$ |

Thermal Characteristic

| | | | |
|--|-----------------|-----|------|
| Thermal Resistance, Junction-to-Case ^(Note 2) | $R_{\theta JC}$ | 3.6 | °C/W |
|--|-----------------|-----|------|

Electrical Characteristics (TC=25°C unless otherwise noted)

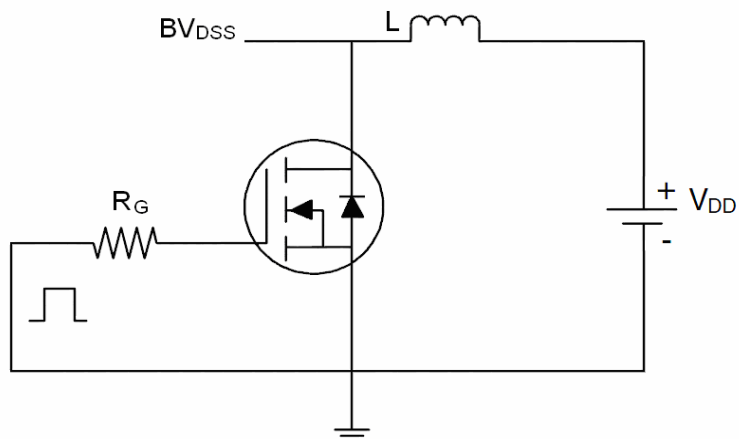
| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|--|--------------|--|-----|------|-----------|------------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=250\mu A$ | 30 | 33 | - | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=30V, V_{GS}=0V$ | - | - | 1 | μA |
| Gate-Body Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 100 | nA |
| On Characteristics ^(Note 3) | | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=250\mu A$ | 1 | 1.6 | 3 | V |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS}=10V, I_D=12A$ | - | 4.8 | 5.5 | m Ω |
| | | $V_{GS}=4.5V, I_D=10A$ | - | 8.2 | 9.5 | |
| Forward Transconductance | g_{FS} | $V_{DS}=10V, I_D=12A$ | 30 | - | - | S |
| Dynamic Characteristics ^(Note 4) | | | | | | |
| Input Capacitance | C_{iss} | $V_{DS}=15V, V_{GS}=0V,$ $F=1.0MHz$ | - | 1265 | - | PF |
| Output Capacitance | C_{oss} | | - | 600 | - | PF |
| Reverse Transfer Capacitance | C_{rss} | | - | 130 | - | PF |
| Switching Characteristics ^(Note 4) | | | | | | |
| Turn-on Delay Time | $t_{d(on)}$ | $V_{DD}=15V, I_D=12A$ $V_{GS}=10V, R_{GEN}=6\Omega$ | - | 18 | - | nS |
| Turn-on Rise Time | t_r | | - | 10 | - | nS |
| Turn-Off Delay Time | $t_{d(off)}$ | | - | 34 | - | nS |
| Turn-Off Fall Time | t_f | | - | 10 | - | nS |
| Total Gate Charge | Q_g | $V_{DS}=15V, I_D=12A,$ $V_{GS}=10V$ | - | 19 | - | nC |
| Gate-Source Charge | Q_{gs} | | - | 2.7 | - | nC |
| Gate-Drain Charge | Q_{gd} | | - | 2.5 | - | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage ^(Note 3) | V_{SD} | $V_{GS}=0V, I_S=12A$ | - | 0.85 | 1.2 | V |
| Diode Forward Current ^(Note 2) | I_S | | - | - | 25 | A |
| Reverse Recovery Time | t_{rr} | $T_J = 25^\circ C, I_F = 12A$ $di/dt = 100A/\mu s$ (Note3) | - | - | 47 | nS |
| Reverse Recovery Charge | Q_{rr} | | - | - | 25 | nC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | |

Notes:

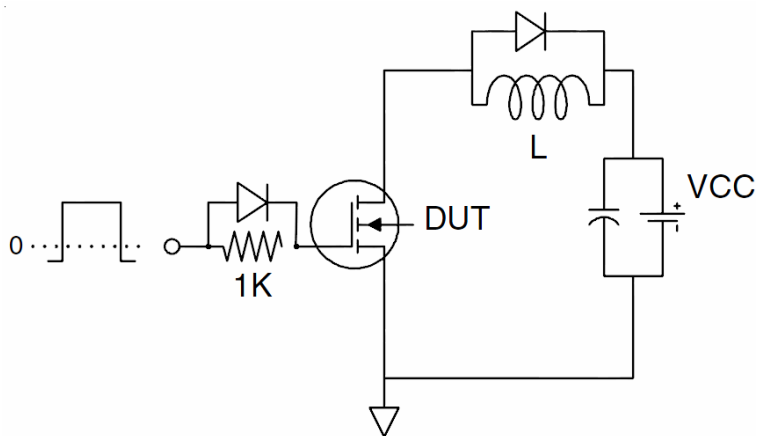
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition: $T_J=25^\circ C, V_{DS}=15V, V_G=10V, L=0.1mH, R_g=25\Omega$

Test Circuit

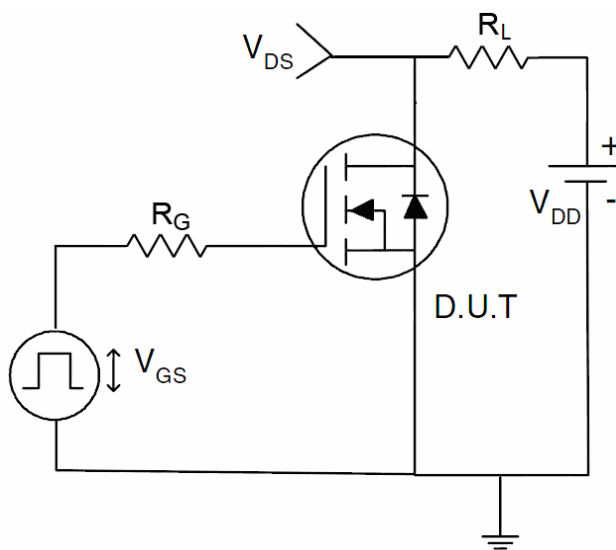
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

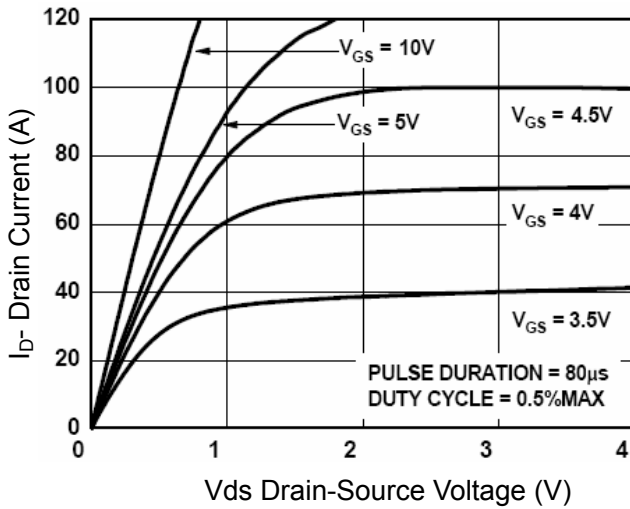


Figure 1 Output Characteristics

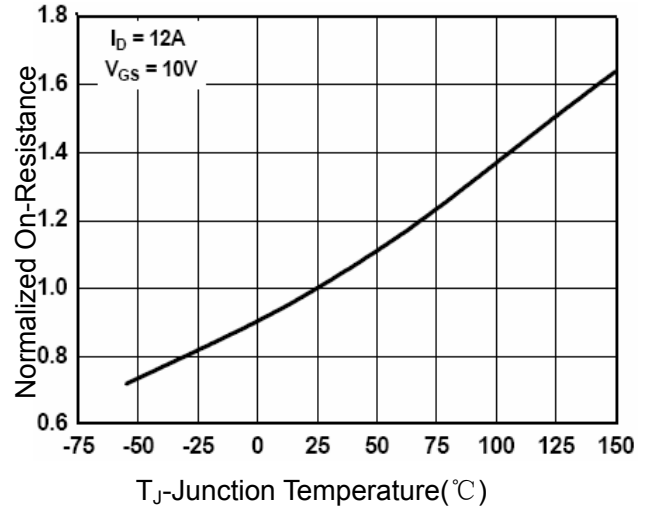


Figure 4 $R_{ds(on)}$ -Junction Temperature

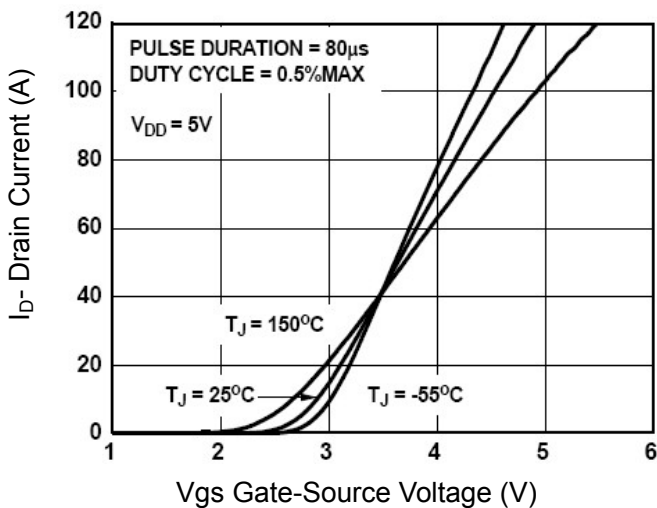


Figure 2 Transfer Characteristics

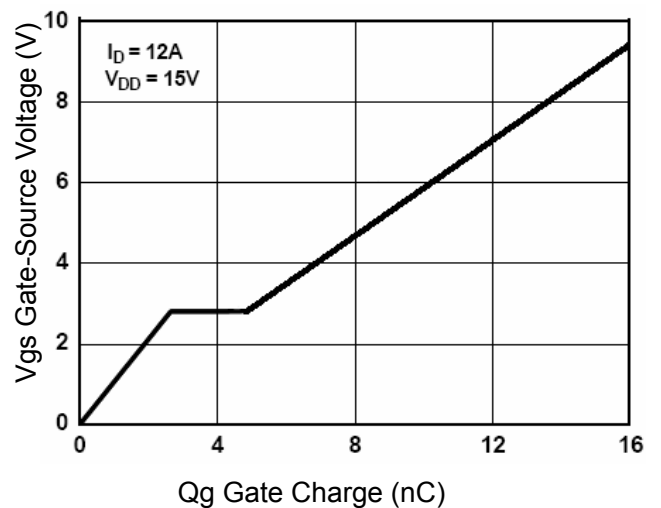


Figure 5 Gate Charge

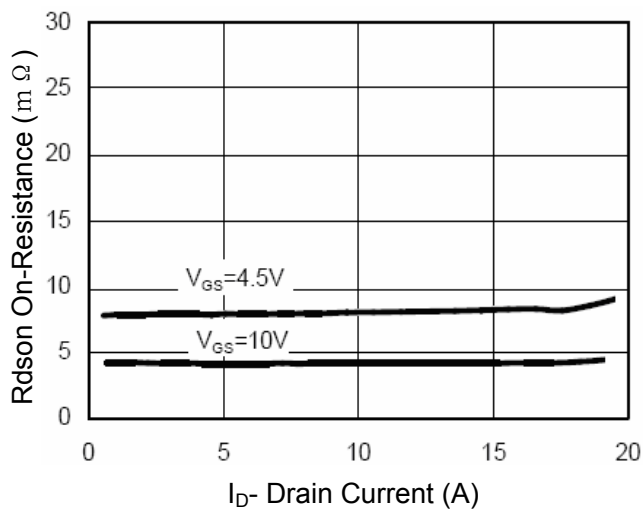


Figure 3 $R_{ds(on)}$ - Drain Current

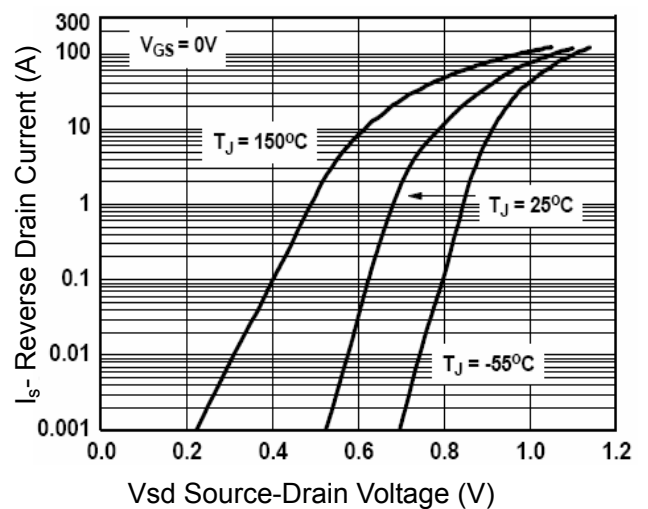
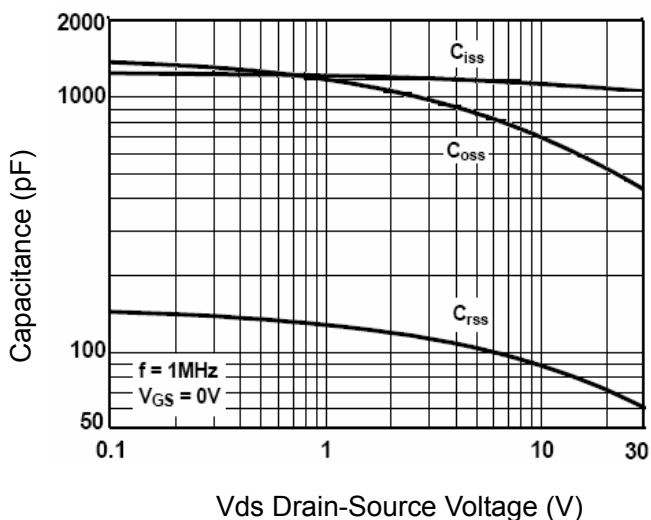
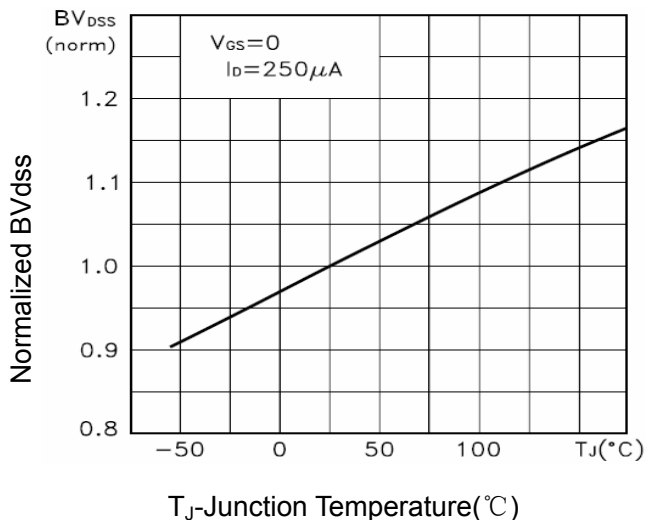


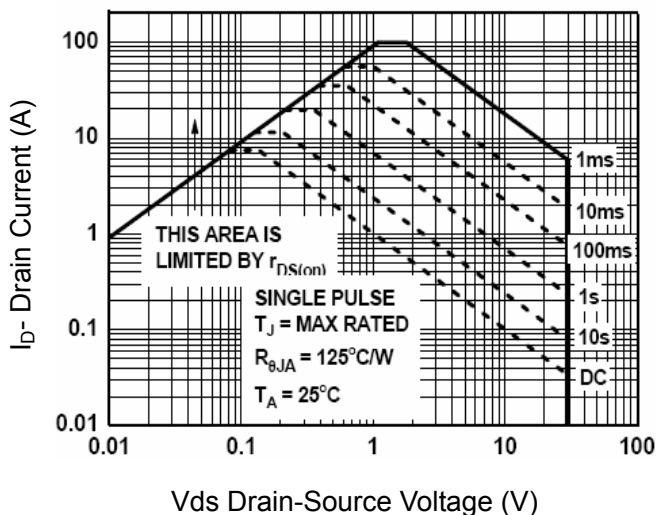
Figure 6 Source- Drain Diode Forward



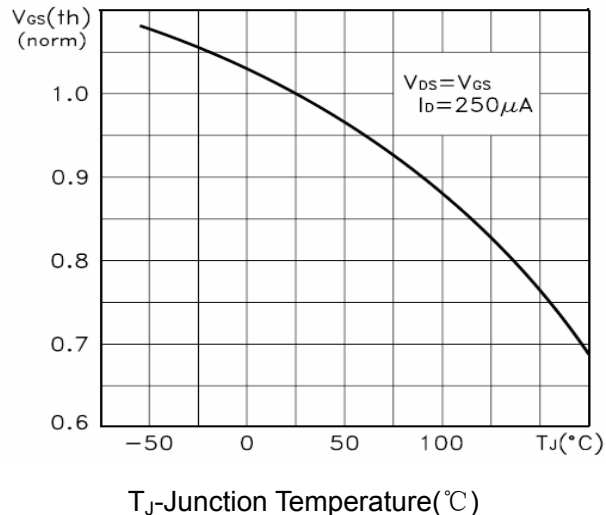
Vds Drain-Source Voltage (V)
Figure 7 Capacitance vs Vds



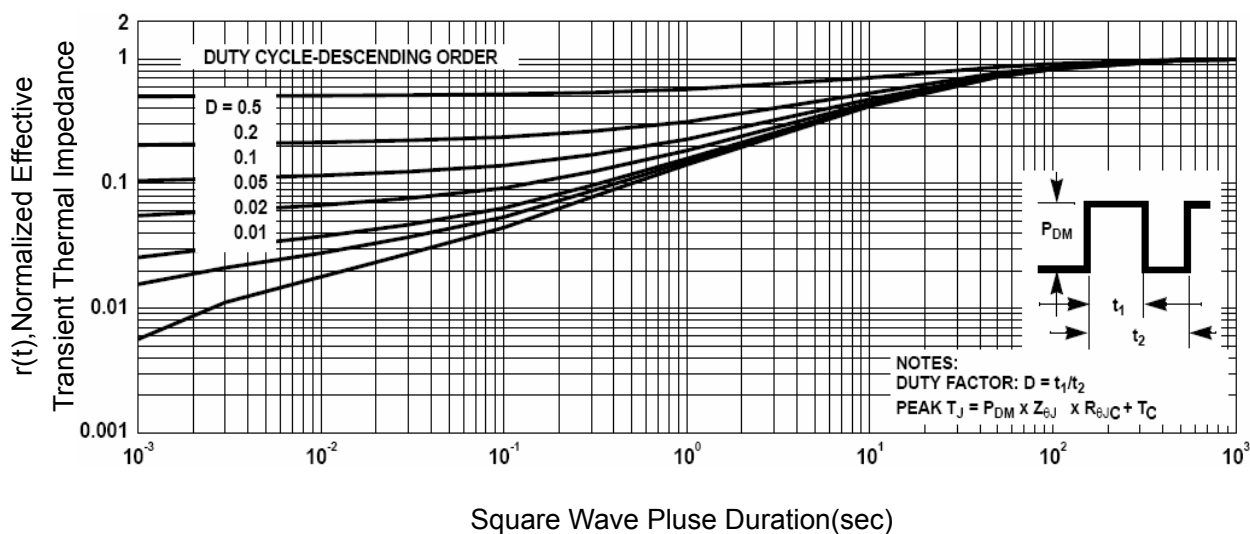
T_J-Junction Temperature(°C)
Figure 9 BV_{DSS} vs Junction Temperature



Vds Drain-Source Voltage (V)
Figure 8 Safe Operation Area

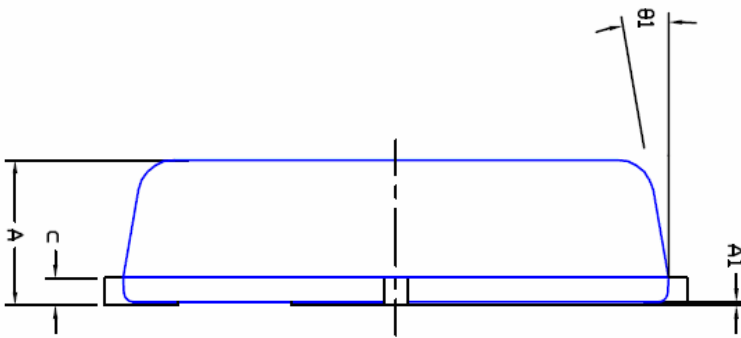
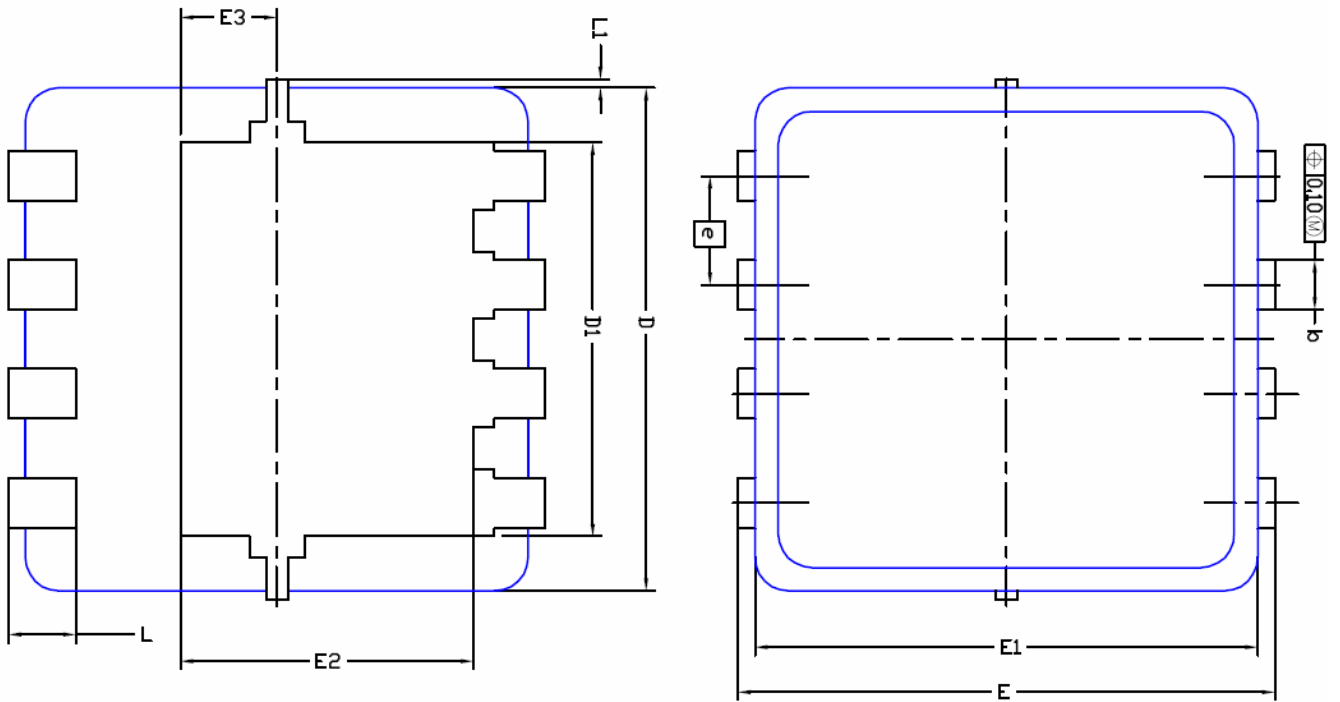


T_J-Junction Temperature(°C)
Figure 10 V_{GS(th)} vs Junction Temperature



Square Wave Pulse Duration(sec)
Figure 11 Normalized Maximum Transient Thermal Impedance

DFN3X3 EP Package Information



| DIM. | MILLIMETERS | | | INCHES | | |
|------|-------------|-------|-------|-----------|--------|--------|
| | MIN | NOM | MAX | MIN | NOM | MAX |
| A | 0,700 | 0,80 | 0,900 | 0,0276 | 0,0315 | 0,0354 |
| A1 | 0,00 | --- | 0,05 | 0,000 | --- | 0,002 |
| b | 0,24 | 0,30 | 0,35 | 0,009 | 0,012 | 0,014 |
| c | 0,10 | 0,152 | 0,25 | 0,004 | 0,006 | 0,010 |
| D | 3,00 BSC | | | 0,118 BSC | | |
| D1 | 2,35 BSC | | | 0,093 BSC | | |
| E | 3,20 BSC | | | 0,126 BSC | | |
| E1 | 3,00 BSC | | | 0,118 BSC | | |
| E2 | 1,75 BSC | | | 0,069 BSC | | |
| E3 | 0,575 BSC | | | 0,023 BSC | | |
| e | 0,65 BSC | | | 0,026 BSC | | |
| L | 0,30 | 0,40 | 0,50 | 0,0118 | 0,0157 | 0,0197 |
| L1 | 0 | --- | 0,100 | 0 | --- | 0,004 |
| θ1 | 0° | 10° | 12° | 0° | 10° | 12° |